

Electronic supplementary information

Dewetting of ultrathin Ag film with random vacancy defects on a SiO₂ substrate: A molecular dynamics simulation

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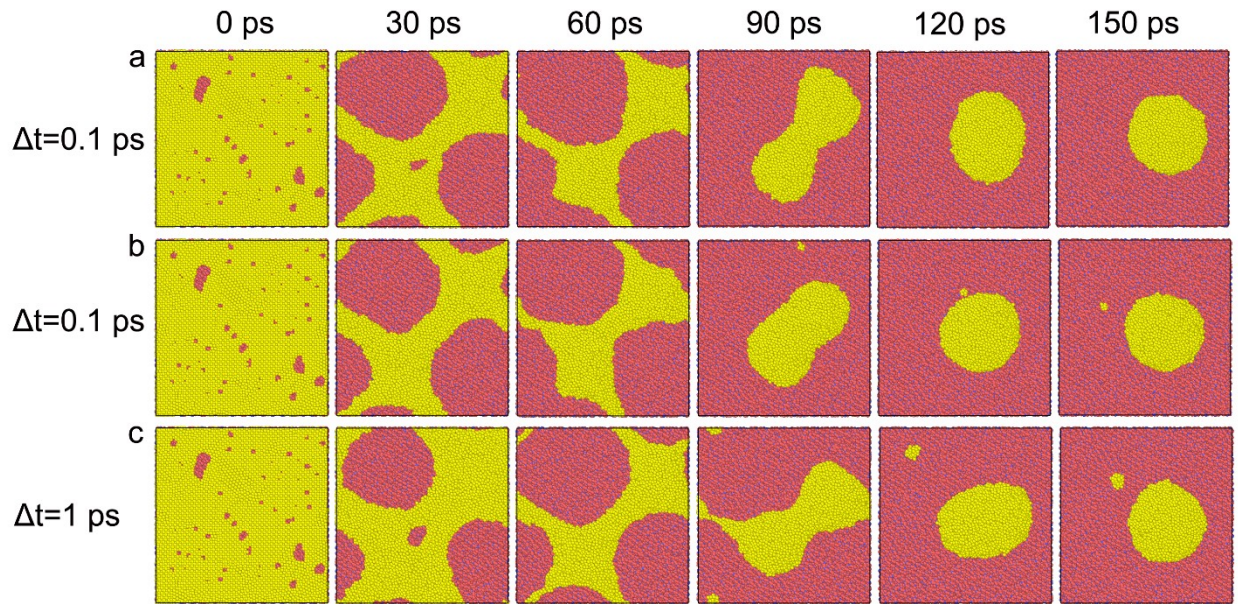


Fig. S1 Time-dependent dewetting patterns of the 0.4 nm thick Ag film with $f=0.1$ for different temperature damping parameter of the thermostat: $\Delta t=0.01$ ps (a); $\Delta t=0.1$ ps (b), and $\Delta t=1$ ps (c).